

Reliability and validity of the Korean version of the Impact of Event Scale-Revised

Lim HK, Woo JM, Kim TS, Kim TH, Choi KS, Chung SK, Chee IS, Lee KU, Paik KC, Seo HJ, Kim W, Jin B, Chae JH.

Comprehensive psychiatry

2009; 50(4):385-390

ARTICLE IDENTIFIERS

DOI: 10.1016/j.comppsych.2008.09.011

PMID: 19486738

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: not available

pISSN: 0010-440X

eISSN: 1532-8384

OCLC ID: 01564585

CONS ID: not available

US National Library of Medicine ID: 0372612

This article was identified from a query of the SafetyLit database.